

Notice of References Cited	Application/Control No. 10/718,400		Applicant(s)/Patent Under Reexamination YANAVI, AURA	
	Examiner Samuel G. Neway		Art Unit 2194	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,477,471	11-2002	Hedstrom et al.	702/34
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
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	J	US-			
	K	US-			
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FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	McConnell, "Gauging Software Readiness with Defect Tracking", 1997 IEEE Software, pp. 135-136.
	V	Yu et al., "An Analysis of Several Software Defect Models", IEEE Transactions on Software Engineering, vol. 14 no. 9, September 1988.
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.